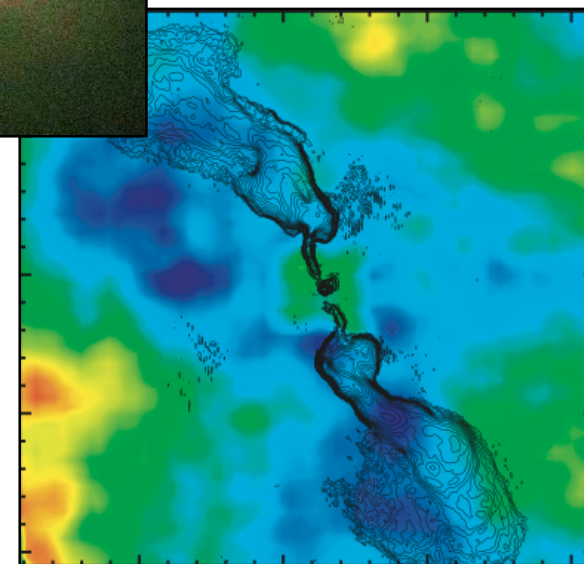
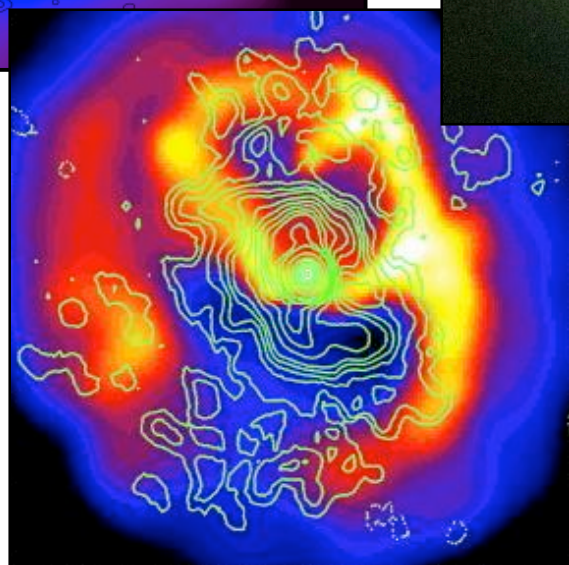
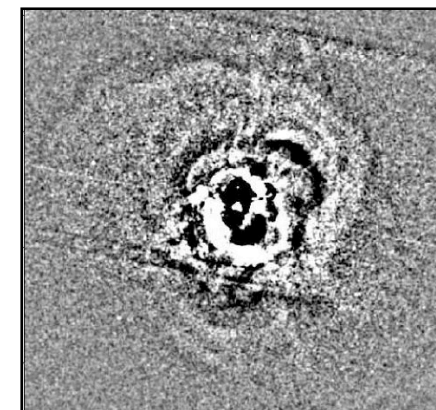
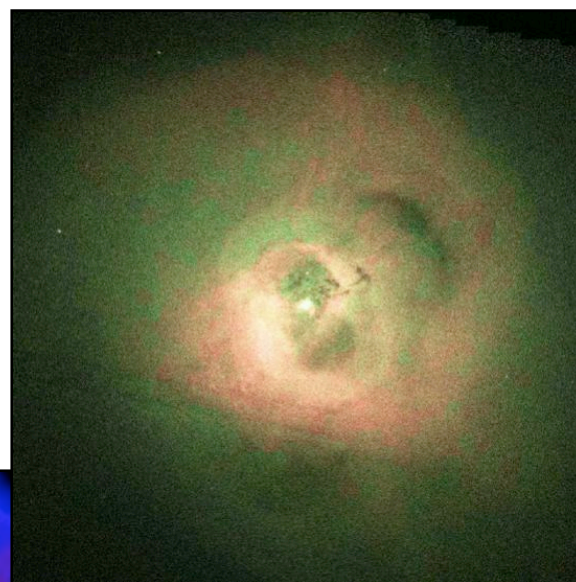
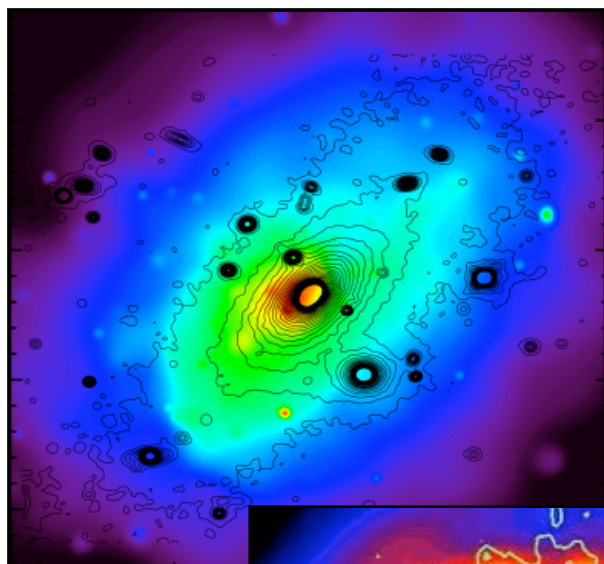




Analysis of Extended Sources





Analysis Guide: Extended Sources – CIAO 3.0

http://cxc.harvard.edu/ciao/guides/esa.html

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Analysis Guide: Extended Sources

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Scientific analysis of even X-ray point sources can be a complicated process. This situation is exacerbated for extended sources, such as clusters of galaxies or supernova remnants, due to spatial variations in the detector properties. We loosely define an extended source as any object larger than several times the telescope point spread function and/or encompassing a region large enough to exhibit significant variations in the detector properties. Many of the typical analysis tasks for extended sources are not required for point source analysis. In this guide, we provide threads for several common extended source analysis tasks; examples based on archived Chandra ACIS datasets are used.

Before analyzing any data, make sure that it has been processed with the latest calibration. There are also some filtering choices that should be considered. Both of these topics are outlined in the [ACIS Data Preparation](#) analysis guide.

The following threads are referenced:

- [ACIS Background Subtraction](#)
- [Obtain and Fit a Radial Profile](#)
- [Detecting Sources - Overview](#)
- [Detecting Sources - Using vtpdetect](#)
- [Detecting Sources - Using wavdetect](#)
- [Displaying the FFP Regions Covered by a Source](#)
- [Weighting ARFs and RMFs: multiple sources](#)
- [Extracting Extended Source Spectra and Responses](#)
- [Sherpa: Fitting FITS Image Data with Multi-Component Source Models](#)
- [Sherpa: Using an Exposure Map in Fitting Image Data](#)
- [Calculating Spectral Weights](#)
- [Use merge_all Script to Compute ACIS Exposure Maps](#)
- [Compute Single Chip ACIS Exposure Map](#)
- [Compute Multiple Chip ACIS Exposure Map](#)
- [Create an Image of Diffuse Emission](#)

Thread: [ACIS Background Subtraction](#)

Determining the background for spectral analyses or measuring surface brightness profiles can be difficult for extended sources where the object covers a large fraction of the chip. For datasets which do not allow a local background to be determined, the ACIS calibration team had compiled a set of experimental "blank-sky" datasets. These files can be used to create background spectra for spectral fitting or images for spatial analyses tailored to a specific observation. When working with these background files, however, the event file must be filtered to match how the "blank-sky" files were created.

Threads: [Detecting Sources in Imaging Observations - Overview](#)
[Detecting Sources in Imaging Observations - Using vtpdetect](#)
[Detecting Sources in Imaging Observations - Using wavdetect](#)

Observations of extended sources often contain serendipitous point sources not directly associated with the desired target. Although such objects may be scientifically interesting in their own right, they can be a source of complication for the analysis of any diffuse emission from the intended source. Most users will want to filter out any bright point sources before determining, for example, a radial surface brightness profile in order to avoid erroneous sharp discontinuities, or before fitting spectral models to avoid biasing the resulting fit towards an incorrect physical model. Removing point sources from the event file prior to any of these tasks is straightforward in CIAO using the [dmcopy](#) command; however, the first step is to identify these objects. The CIAO Detect package contains two tools which provide the ability to work in complex fields with both point and extended sources - [vtpdetect](#) and [wavdetect](#).

Threads: [Use merge_all Script to Compute ACIS Exposure Maps and Fluxed Images](#)

Online documentation

<http://cxc.harvard.edu/ciao/guides/esa.html>

- Background subtraction
- Fitting radial profiles
- Source detection
- Weighted RMFs and ARFs
- Computing exposure maps
- 2-D fitting in **Sherpa**



Data preparation

- Standard re-processing (bad aspect, flares, etc.)
- CTI-correct data (if ACIS-I chips) [`acis_process_events`]
- Correct temporal drift in gain [`corr_tgain, acis_process_events`]
- Re-calculate PI values [`acis_process_events`]

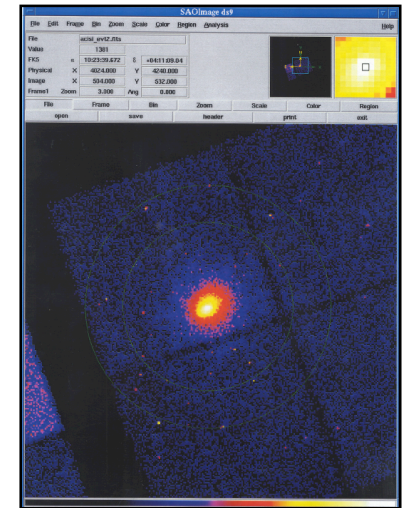
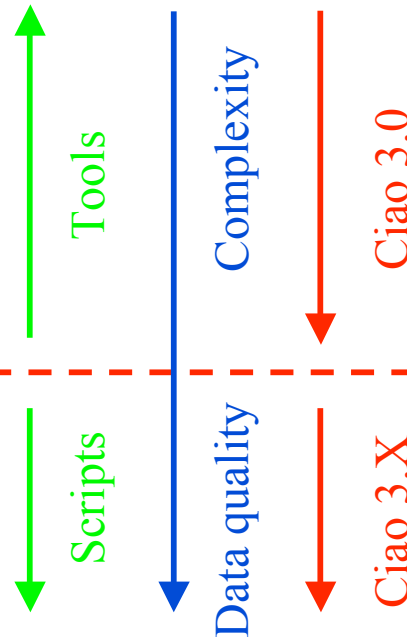
Free advice

- Work in PI units
- Analyse FI and BI spectra jointly (not combined)
- Analyze multiple OBSIDs jointly (not combined)
- Be suspicious of fits below ~ 0.6 keV
- Save your receipt



Cluster Typical analysis scenario

- Integrated spectral analysis
 - Flux-corrected images
 - Surface brightness profiles
 - Annular spectral analysis
-
- Deprojected spectral analysis
 - 2D spectral mapping



THE INSIGNIFICANCE OF GLOBAL HEATING IN THE ABELL 1863 CLUSTER X-RAY ANALYSIS

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 MIT Kavli Institute for Astrophysics and Space Research, Cambridge, MA 02139
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ABSTRACT

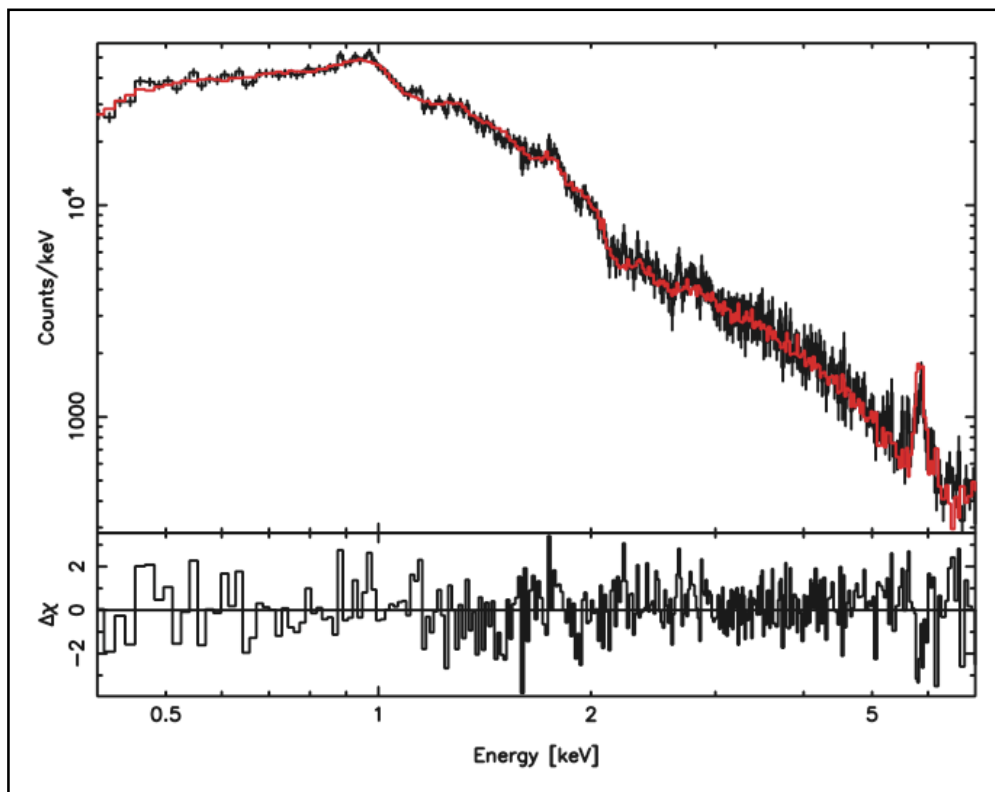
We report on a Chandra observation of the massive, relaxed cluster Abell 1863. We detect a clear temperature gradient in the X-ray emitting gas from $kT \sim 4$ keV in the core out to the cluster edge to roughly 7 keV at the core, and a striking increase in the complexity of the gas beyond the core radius. The temperature gradient is consistent with a cooling flow model with a cooling rate of $\sim 100 M_{\odot} \text{ yr}^{-1}$. Within the core ($r < 40$ kpc), the ratio of emission line to continuum is consistent with the gas ionization state from optical data. We find an apparent correlation between the X-ray emission line profiles and enhanced metallicity measured in the core $> 100\%$ of the cluster. We show that the apparent correlation of the emission line profiles with the metallicity is a result of the complex structure of the gas in the core. We show that the X-ray emission line profiles are consistent with the results of a model in which the cooling flow is heated by the X-ray emission line profiles in the core. We show that the X-ray emission line profiles are consistent with the results of a model in which the cooling flow is heated by the X-ray emission line profiles in the core. We show that the X-ray emission line profiles are consistent with the results of a model in which the cooling flow is heated by the X-ray emission line profiles in the core.

1. INTRODUCTION

Galaxy clusters frequently have high X-ray surface brightness cores due to thermal emission from dense gas. About a substantial and persistent hot source, the high density, hot gas is cooled by radiating away its energy. The cooling flow model is a natural consequence of the fact that the gas is cooled by radiating away its energy. The cooling flow model is a natural consequence of the fact that the gas is cooled by radiating away its energy. The cooling flow model is a natural consequence of the fact that the gas is cooled by radiating away its energy.



Integrated spectral analysis



Procedure

- Find and remove point sources
- Extract spectrum (and background)
- Create weighted ARF
- Create weighted RMF
- Correct ARF for contamination
- Define model and fit
- Save fitted spectrum

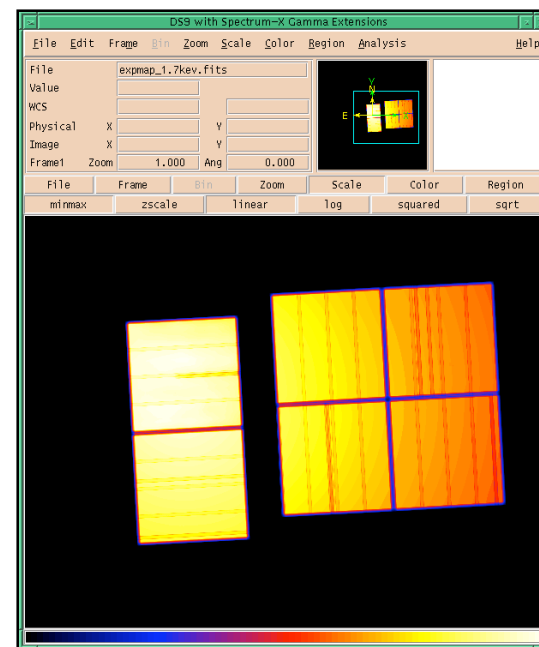
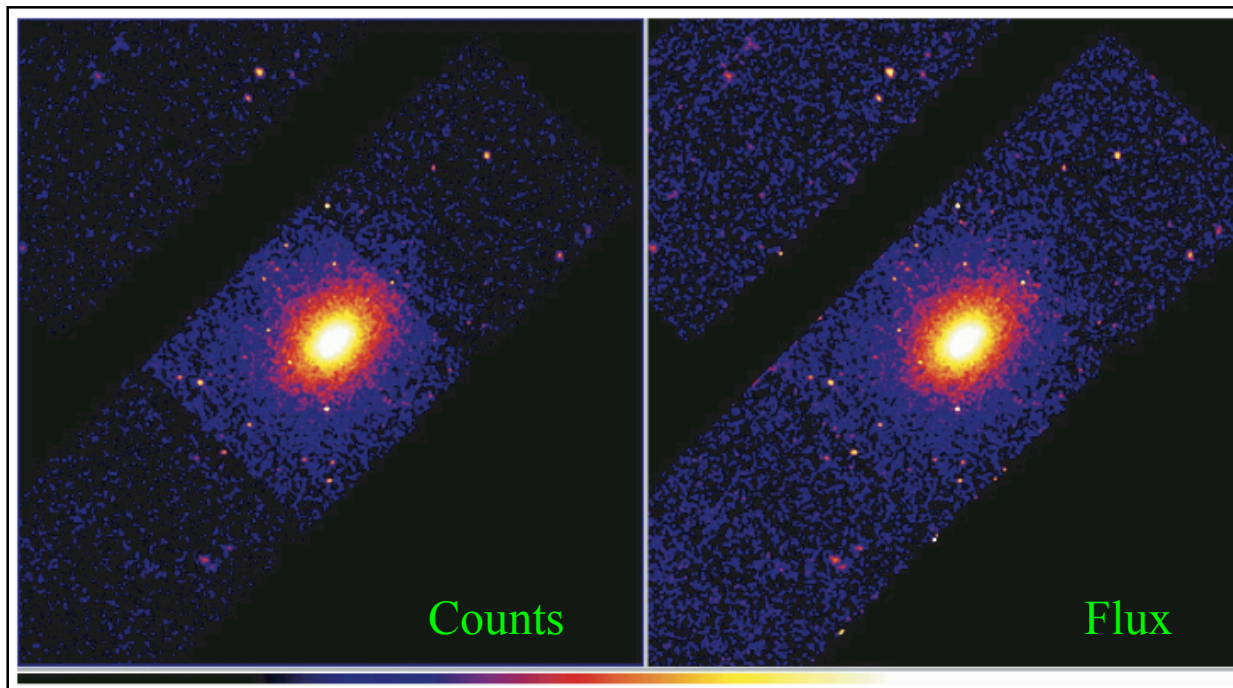
Tools

- `wavdetect`, `dmcopy`
- `dmextract`
- `mkwarf`
- `mkrmf`
- `contamarf`, `mkwarf`, `acisabs`
- `sherpa`

- `dmextract infile="evt2.fits[sky=circle(4024.0,4240.0,300.0)][bin pi]" \`
 `outfile="spect.pi" wmap="det=8"`
- `mkwarf infile="spect.pi[WMAP]" outfile="spec.warf" weightfile="spect.wgt"`
- `mkrmf outfile="spect.wrmf" weights="spect.wgt"`



Flux-corrected images



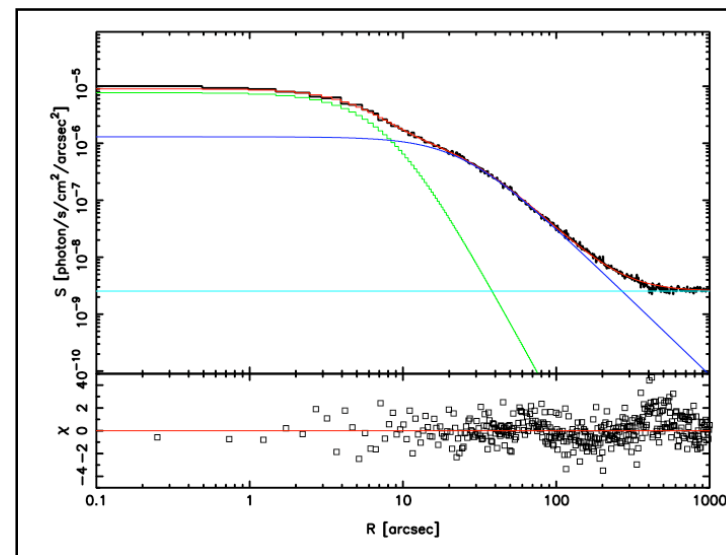
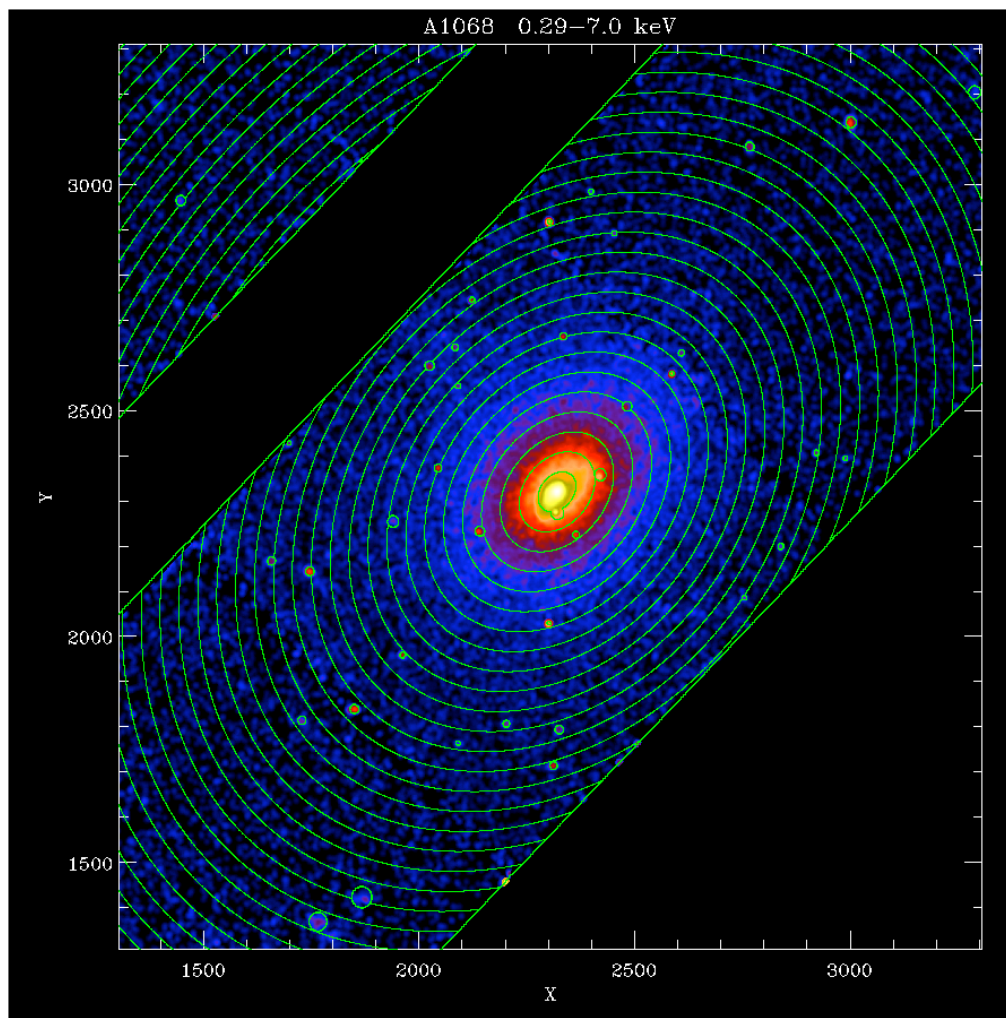
Exposure map

- Start with fitted spectrum (from integrated fit) [[sherpa](#)]
- Create counts image of field [[dmcopy](#)]
- Create instrument map for each chip [[mkinstmap](#)]
- Create exposure map for each chip [[mkexpmap](#)]
- Combine single exposure maps [[dmregrid](#)]
- Divide counts image by exposure map [[dmimgcalc](#)]

Caveat: [mkinstmap](#) does not currently account for the spatial dependence of ACIS contaminant



Surface brightness profiles



- Find and remove point sources
- Define annular regions
- Extract counts in each annulus
- Cut point source regions from exp. map
- Extract exposure in each annulus
- Divide counts by exposure
- Fit \square model to profile

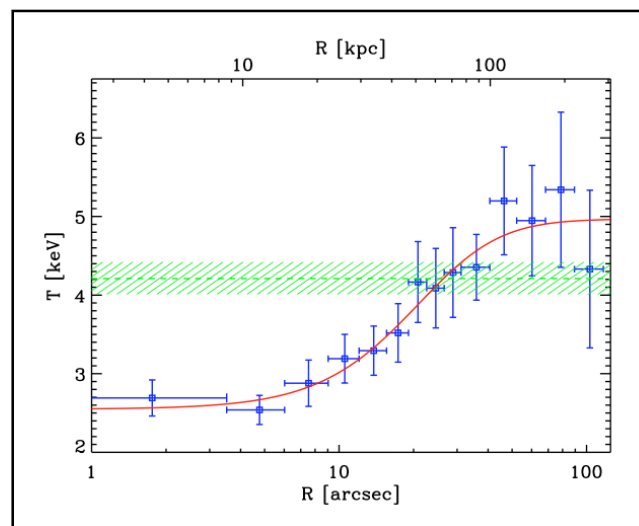
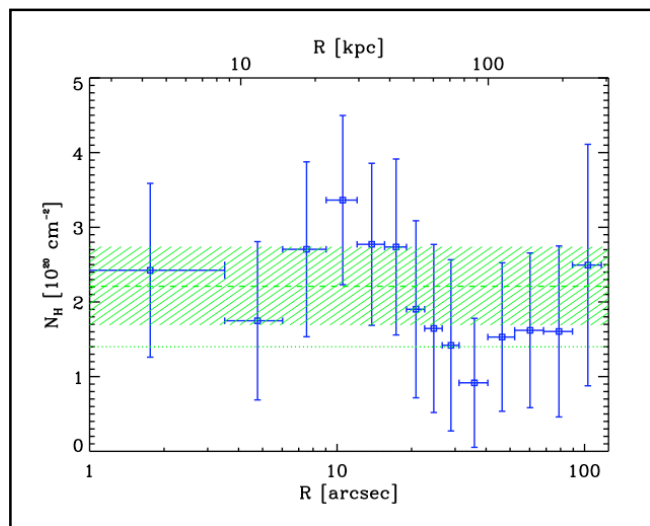
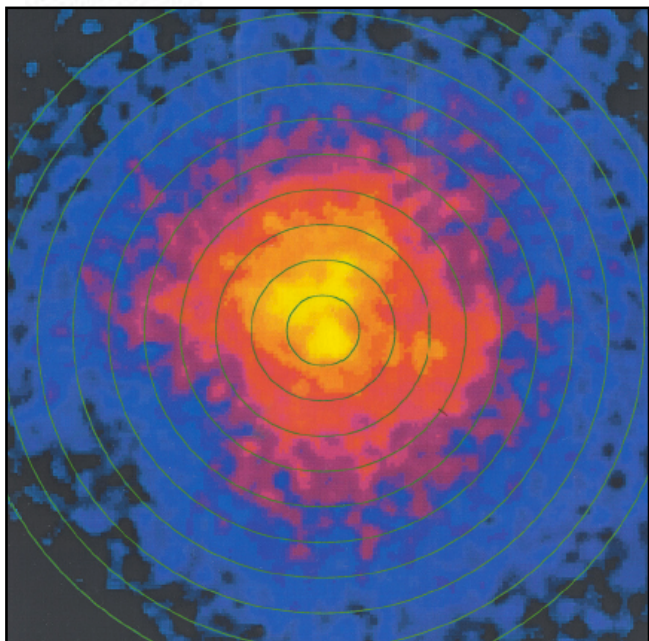
Tools: `dmcopy`, `ds9`, `dmextract`,
`dmtcalc`, `sherpa`



Annular spectral analysis

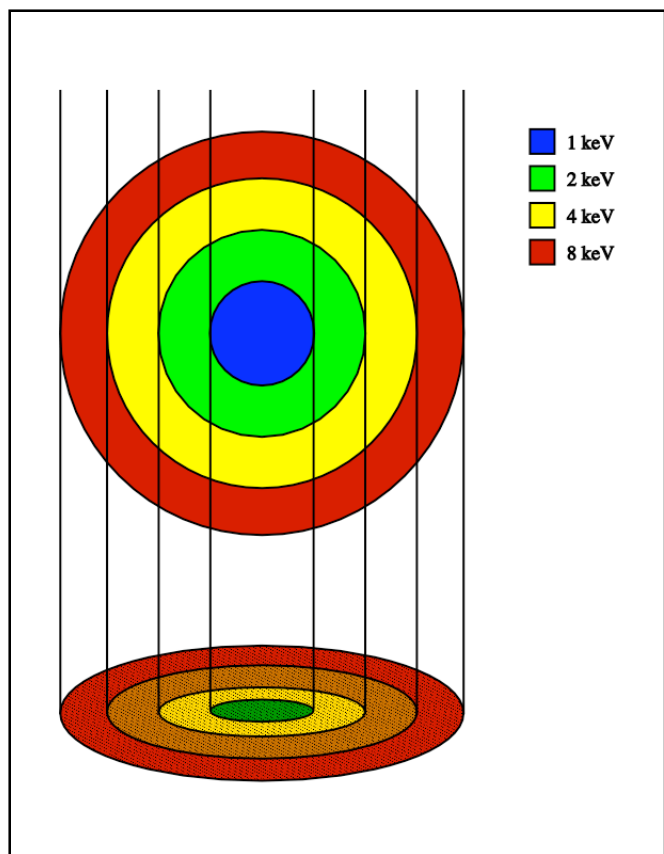
- Cut out point sources [`dmcopy`]
- Define annuli (equal counts?) [`ds9`, (S-Lang script)]
- Create PHA and weighted RMF/ARF for each annulus [`dmextract`, `mkrmf`, `mkwarf`]
- Define spectral model [`sherpa`]
- Repeat spectral fit for each annulus

Tip: Write a S-Lang script to loop over annuli





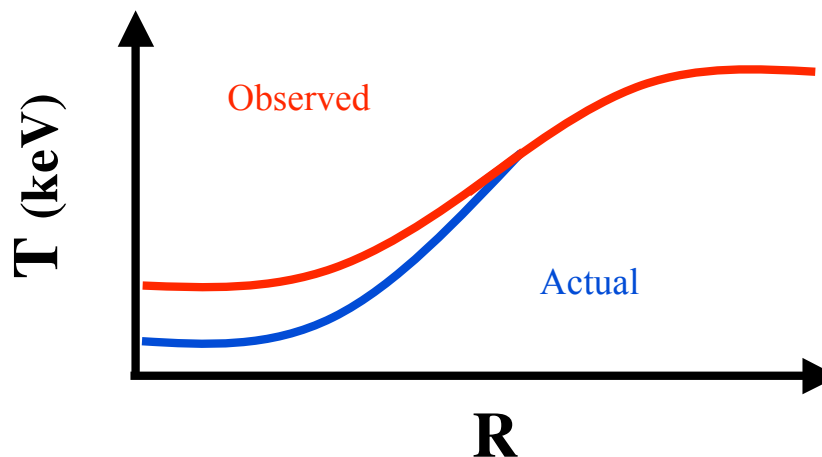
Deprojected spectral analysis



For an assumed geometry, one can calculate the partial volumes, V_{ij} , which contribute to any projected annulus

Problem: Projected spectra contain contributions for all annuli along line of sight

Effect: Measured $\langle T \rangle$ higher than true value

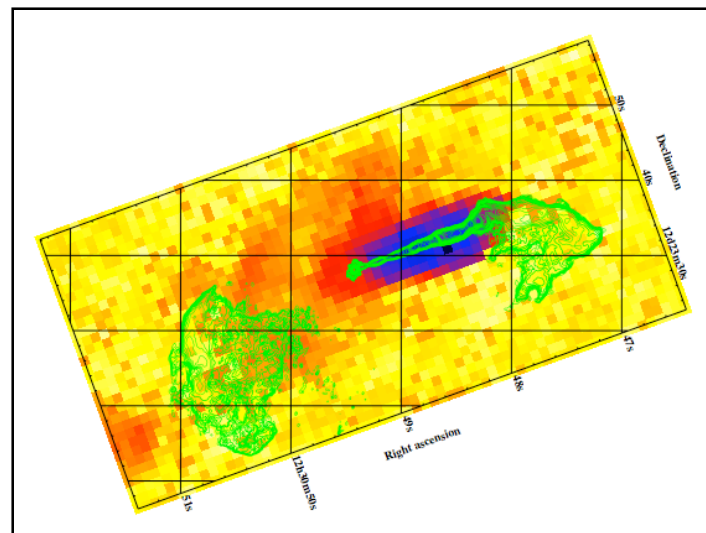


- Solution:**
- Calculate volume fractions
 - Define custom spectral model
 - Fit data from all shells simultaneously
 - Implemented as S-Lang program
 - Coming soon to a thread near you



2D spectral mapping

- Map is just **many** spectral fits
- Define grid of boxes containing counts
- Extract spectrum, calculate RMF/ARF for each box
- Fit model at each grid point
- Write out fit parameters as a function of position
- Can map any fit parameter
- Implemented as S-Lang program



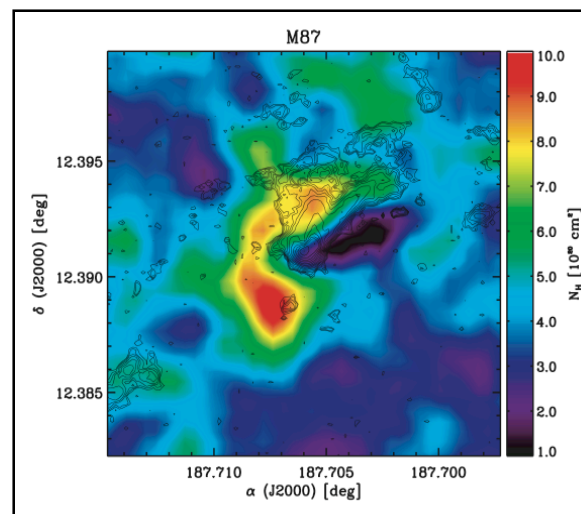
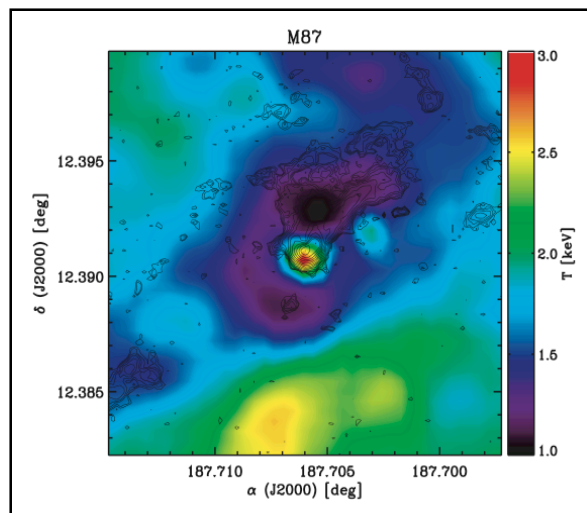
10^3 - 10^4 fits



CPU intensive



Distributed processing





Future development

- Spatial dependence of ACIS contaminant
- S-Lang programs for advanced analysis
- Grating extended source analysis tools
- You tell us

